

**Established
in 2020**

**Nanostructures & Optics
with Swiss Precision**




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ABOUT XRNANOTECH

XRnanotech is the leading Swiss manufacturer of the highest-quality nanostructures and optics: from high-aspect-ratio fresnel zone plates with record breaking resolution to ultra-stable diamond optics and custom 3D-nanostructures for a wide range of applications.

XRnanotech is the culmination of more than 10 years of research and development at the world-renowned Paul Scherrer Institut in Switzerland. The company was incorporated in 2020 with the goal to bring the newest groundbreaking innovations in nano-optics to market.



Vision

To enable optical instruments around the world to reach their full potential.



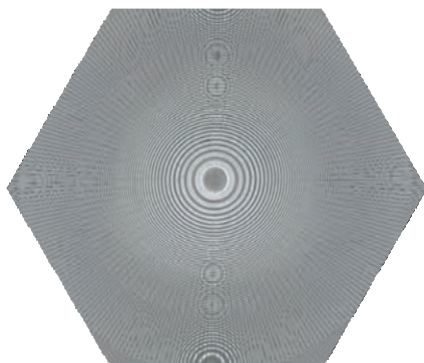
Mission

To develop and fabricate the most innovative nano-optics that reach the highest quality in resolution, efficiency, stability and design.



Team

Our team of engineers and scientists works tirelessly to find the ideal solution for our customers.



Fresnel Zone Plates

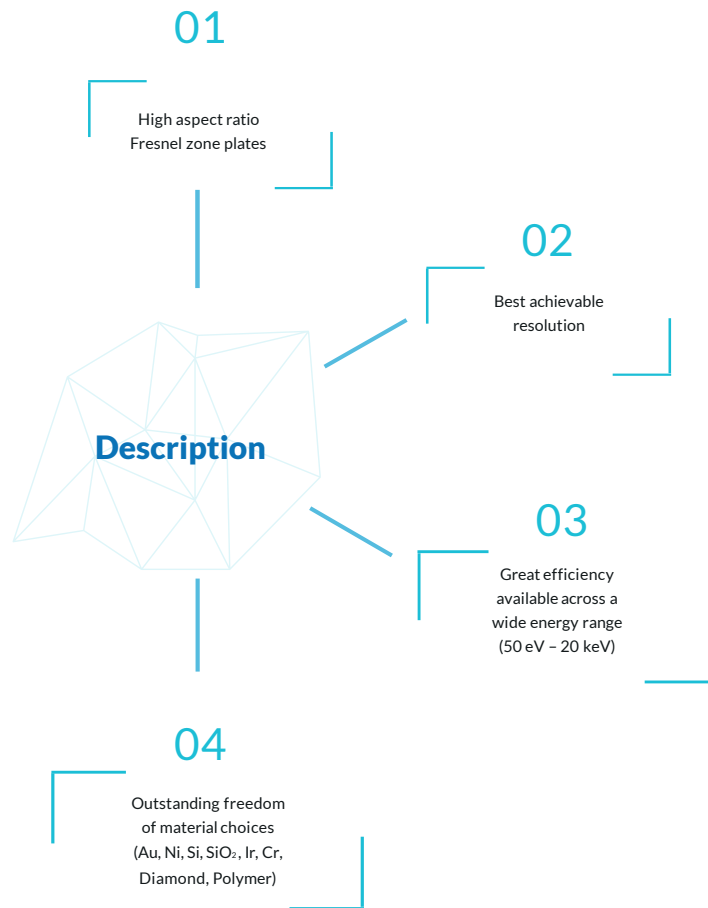
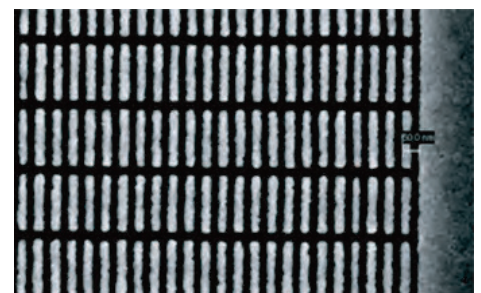


Figure: 1.1
Electroplated gold zone plate for multi-keV X-rays with 50 nm wide and 500 nm high structures



Figure: 1.2
Nickel zone plate for soft X-rays with 25 nm outermost zone width (right).



Specifications

Parameter	Typical Value	Achievable limits
Outermost zone width [nm]	50-100	<10
Diameter[μm]	100-500	>4500
Number of Zones	1000-3000	>30000
Aspect Ratio	10	>30

References

1. S. Gorelick et al. Direct e-beam writing of high aspect ratio nanostructures in PMMA: a tool for diffractive x-ray optics fabrication *Microelectronic Engineering* 87 (2010) p. 1052
2. Vila-Comamala, Joan, et al. "Zone-doubled Fresnel zone plates for high-resolution hard X-ray full-field transmission microscopy." *Journal of Synchrotron Radiation* 19.5 (2012): 705-709.

Specialized Zone Plates

Ultra-high Resolution Zone Plates

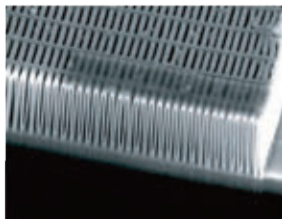
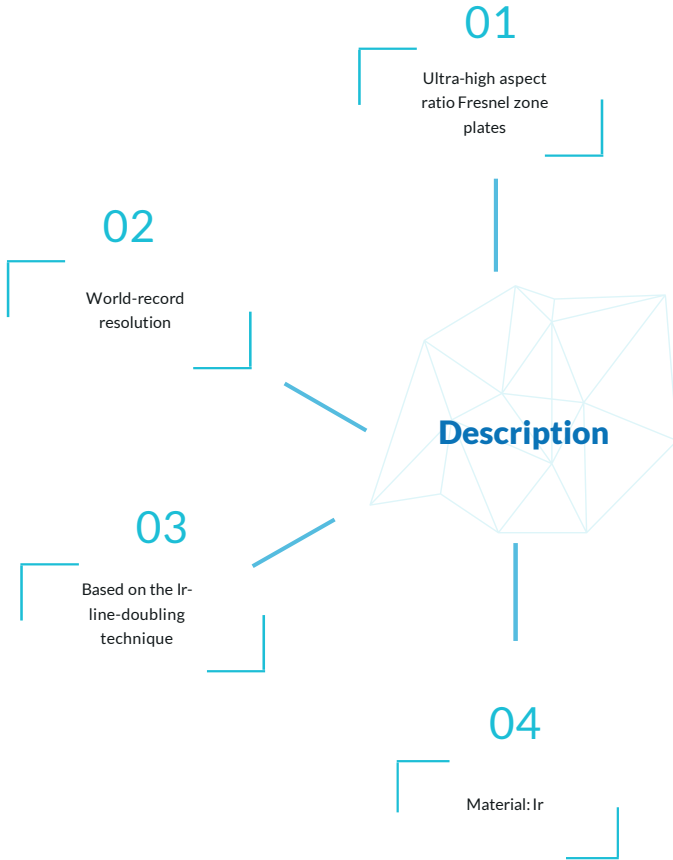


Figure: 2.1
FIB cross-section of 25 nm wide, 550 nm high Ir zone plate

High Efficiency Zone Plates

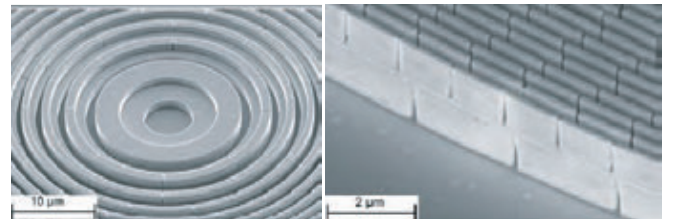
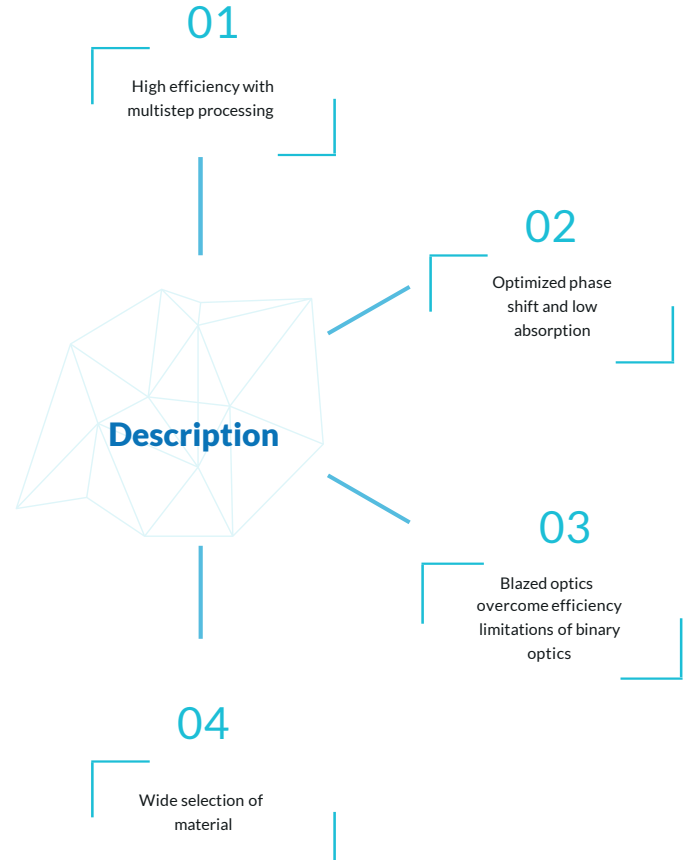


Figure: 2.2
A three-level nickel zone plate with 200 μ m diameter and effective 200 nm smallest zone width

Both technologies combinable to hybrid zone plates- merging great resolution with high efficiency.

Gratings and Beam Splitters

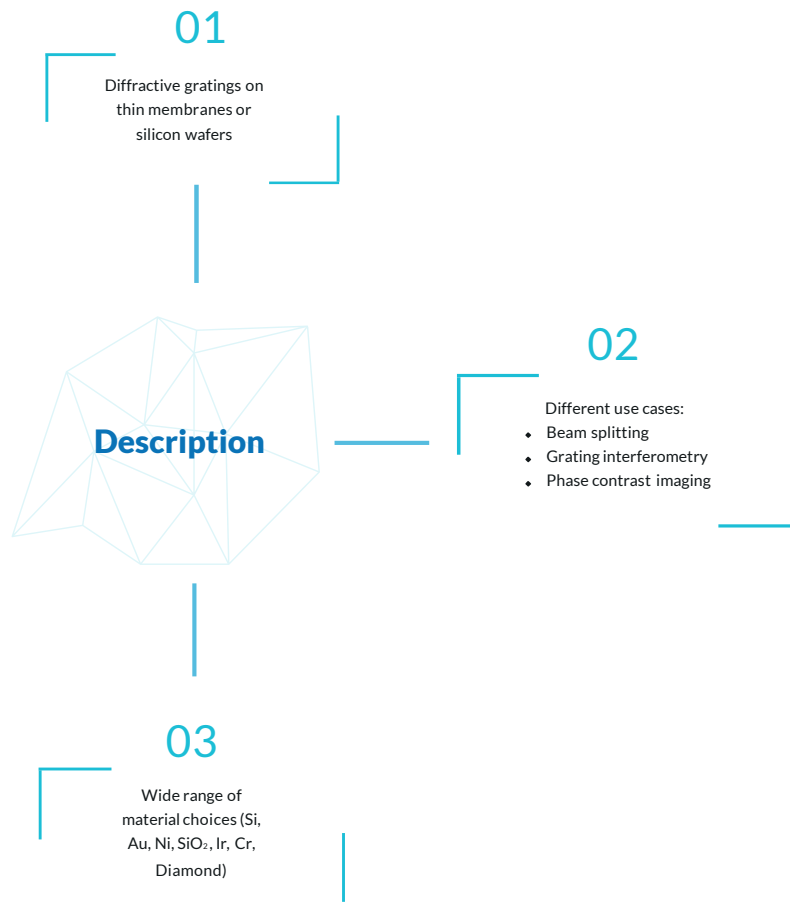


Figure: 3.1
Si grating (p=1800 nm)



Figure: 3.2
Au grating (p=100-200 nm)

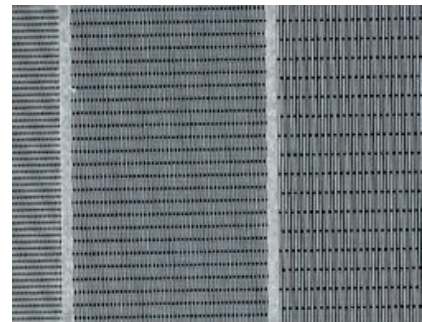
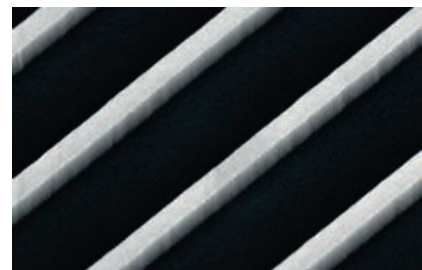


Figure: 3.3
SiO₂ grating (p=500nm)



Specifications

- Gratings can be designed according to customers' needs using various fabrication approaches.

References

1. S. Marathe et al. Development of synchrotron pink beam x-ray grating interferometer at the Diamond Light source I13-2 beamline *Developments in X-Ray Tomography XII* 11113 (2019) p. 1111319
2. S. Rutishauser et al. Exploring the wavefront of hard x-ray free electron laser radiation *Nature Communications* 3(2012), p. 947

Diamond Optics

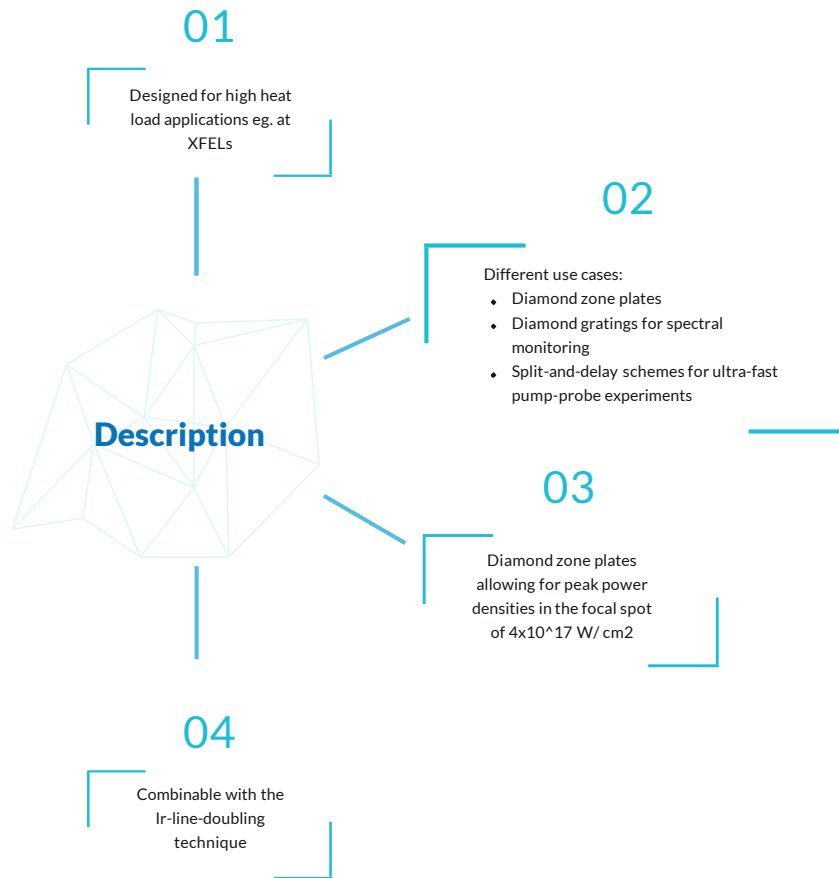


Figure: 4.1
Diamond checkerboard grating

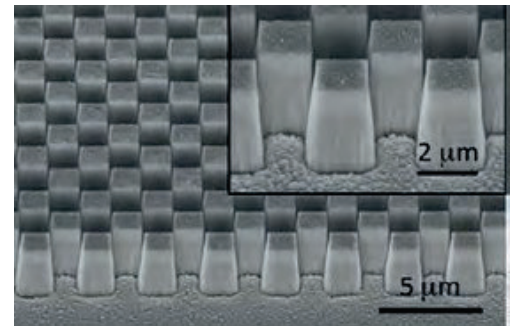
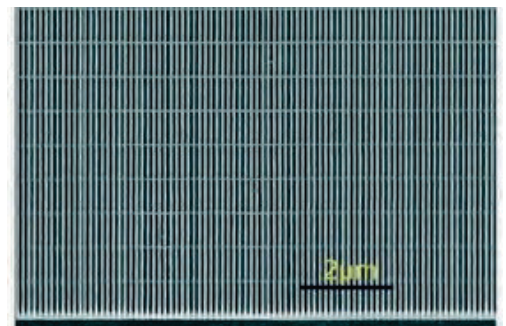


Figure: 4.2
Diamond grating (pitch:150 nm, height: 1200 nm)



Specifications

Parameter	Typical Value	Achievable limits
ΔR_n [nm]	50-100	<10
D [μm]	100-500	>4500
N	1000-3000	>30000
Aspect Ratio	10	>30

References

1. C. David et al. Nanofocusing of hard X-ray free electron laser pulses using diamond based Fresnel zone plates *Scientific Reports* 1 (2011) p. 57
2. M. Makita et al. Diamond diffraction gratings for experiments with intense hard x-rays *microelectronic Engineering* 176 (2017) p. 75

Custom Design Optics

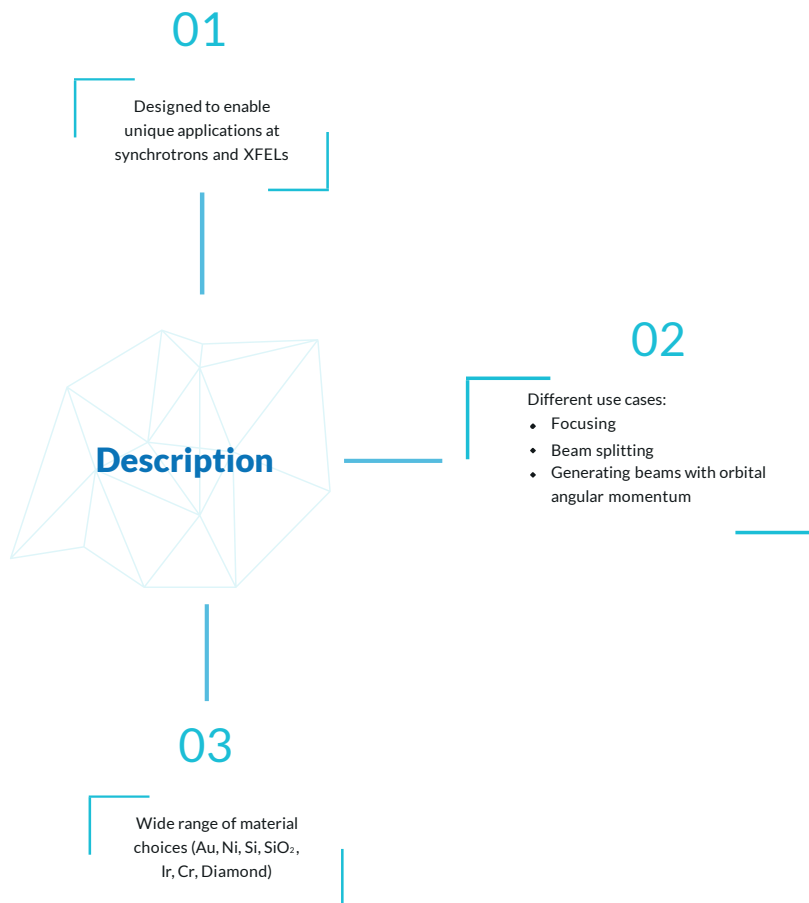


Figure 5.1
Multi-focus zone plate

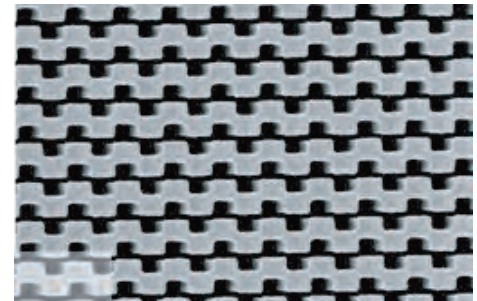


Figure 5.2
Spiral zone plate

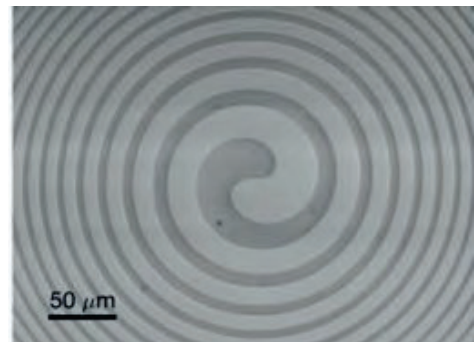
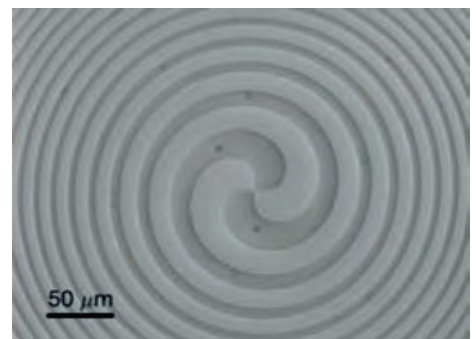


Figure 5.3
Spiral zone plate

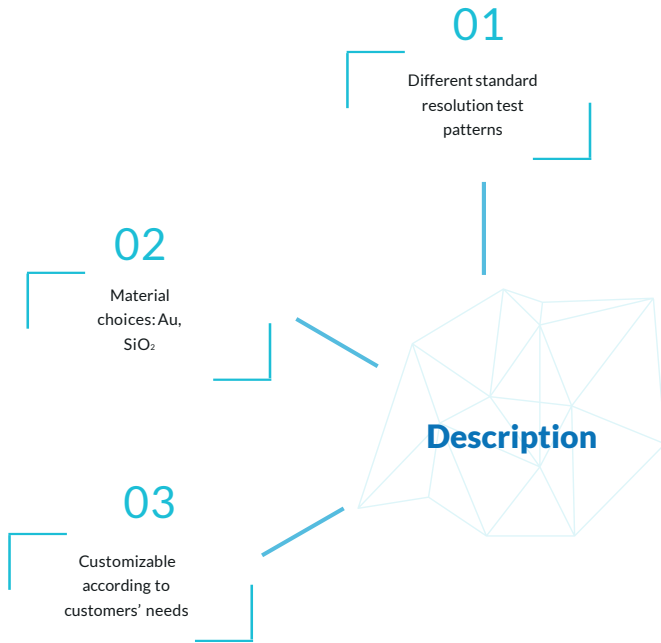


References

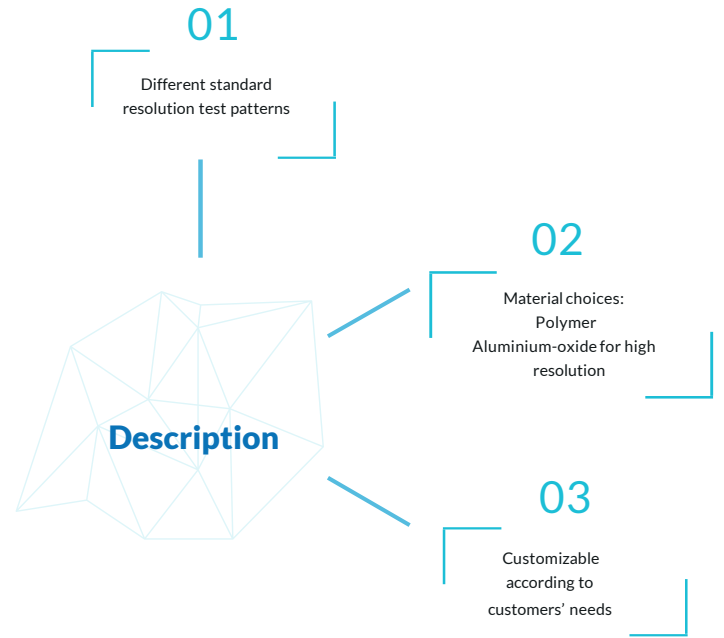
1. F. Döring et al. Multifocus off-axis zone plates for x-ray free-electron laser experiments *Optica* 7 (8) p. 1007
2. P. R. Ribic et al. Extreme-Ultraviolet Vortices at a Free-Electron Laser *Phys. Rev. X* 8.3 (2018)
3. B. Rösner et al. High resolution beam profiling of X-ray free electron laser radiation by polymer imprint development *Optics express* 25 (24), p. 30686

2D and 3D Test Targets

2D Resolution Test Samples



3D Resolution Test Samples



Specifications

Parameter	Typical Value	Achievable limits
Smallest feature [nm]	50-100	<10
Area	1mm x 1mm	3mm x 3mm
Aspect Ratio	10	>30

Specifications

Parameter	Typical Value	Achievable limits
Smallest feature [nm]	<200	<50
Diameter[μm]	100	---
Height of structures [μm]	200	---
Overall height [μm]	250	---



Figure: 6.1
USAF 1951 test target in nm

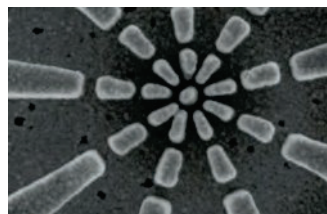


Figure: 6.2
Siemens stars resolution down to 10 nm



Figure: 6.3
Test pattern
"3D Siemens Star"



Figure: 6.4
Tomography of test pattern

Micro-CT Test Targets

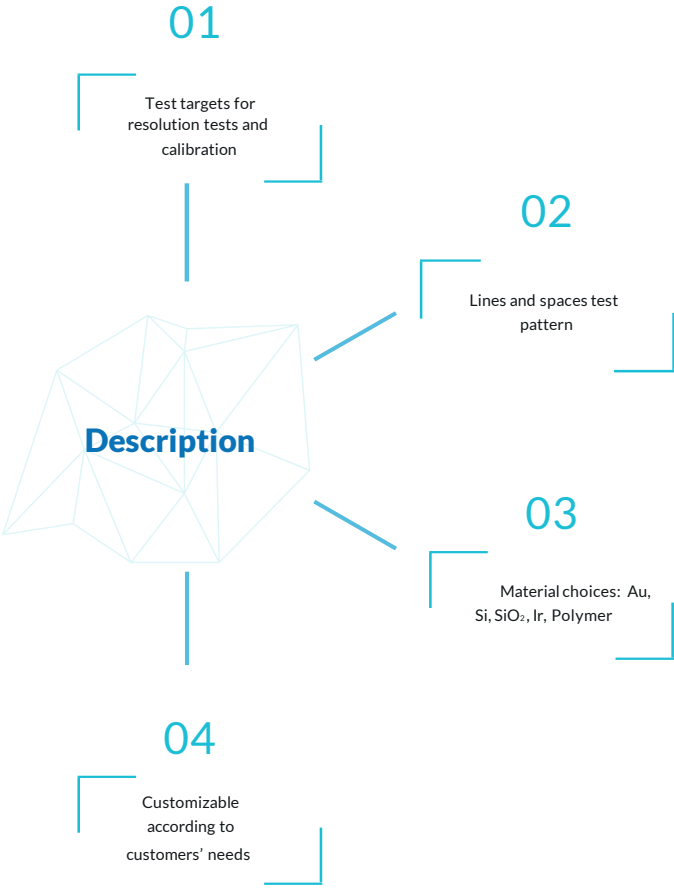
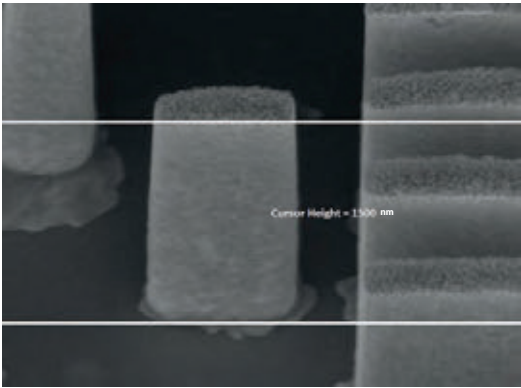


Figure 7.1
Lines and dots down to 200 nm



Figure 7.2
1500 nm tall structures for high contrast



Specifications

Parameter	Typical Value	Achievable limits
Smallest feature [nm]	200	<10
Area	1mm x 1mm	5mm x 5mm
Aspect Ratio	10	>30

3D Nanostructures

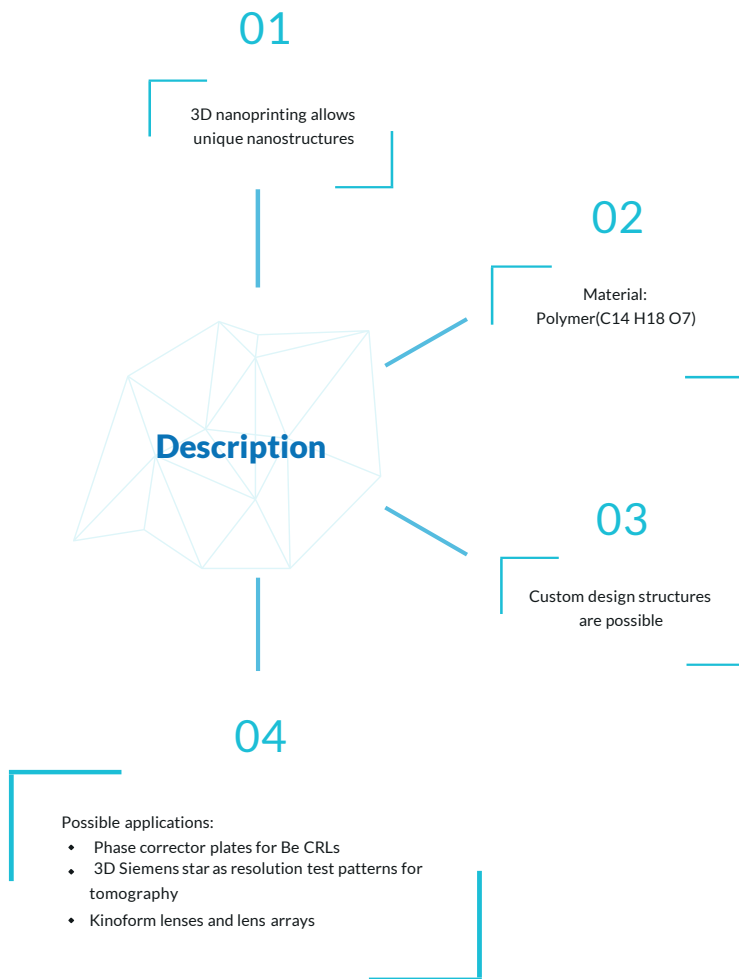


Figure 8.1
Kinoform lens

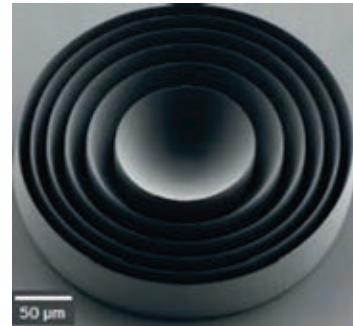


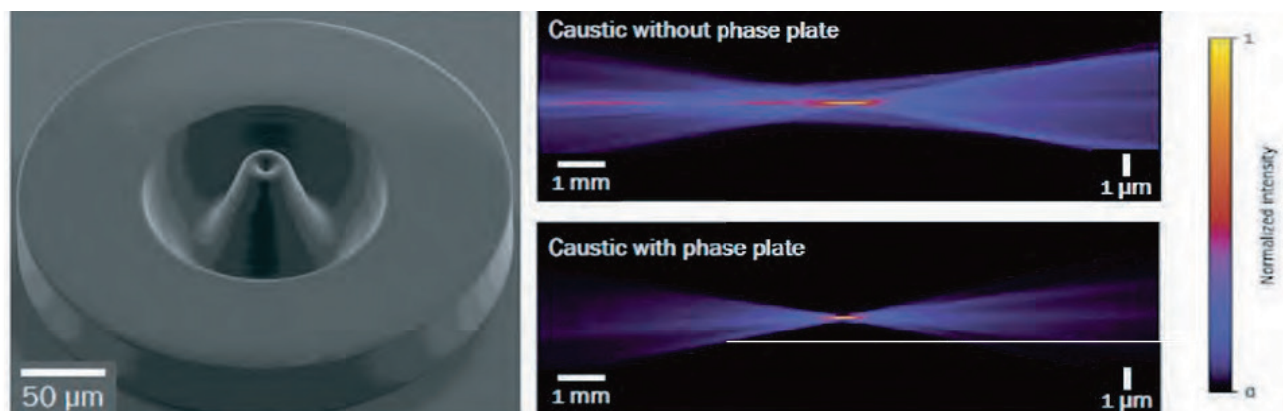
Figure 8.2
Lens array



Figure 8.3
Achromat



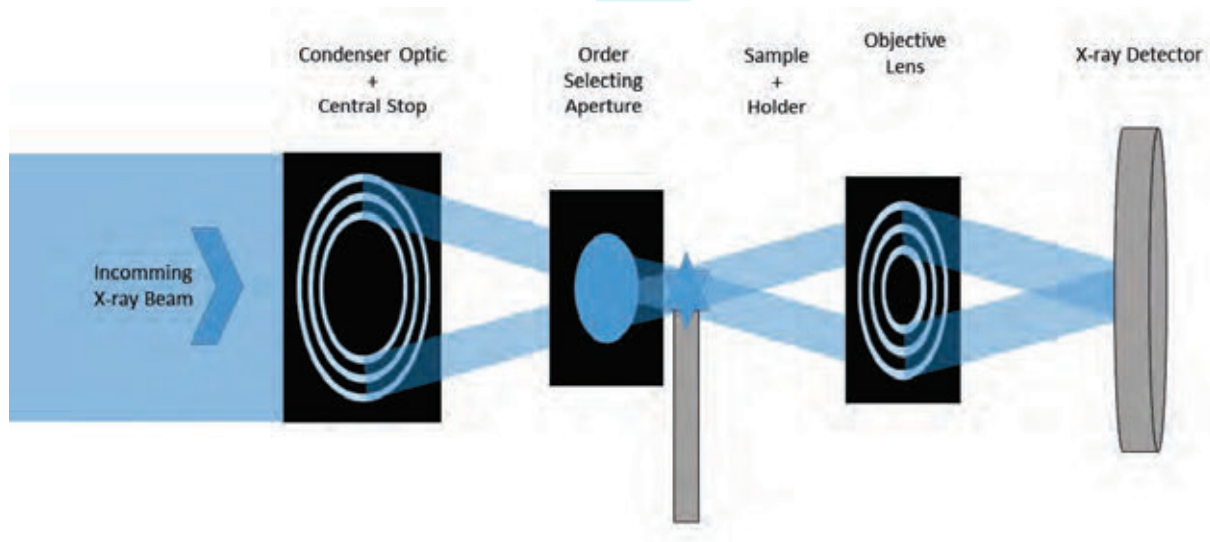
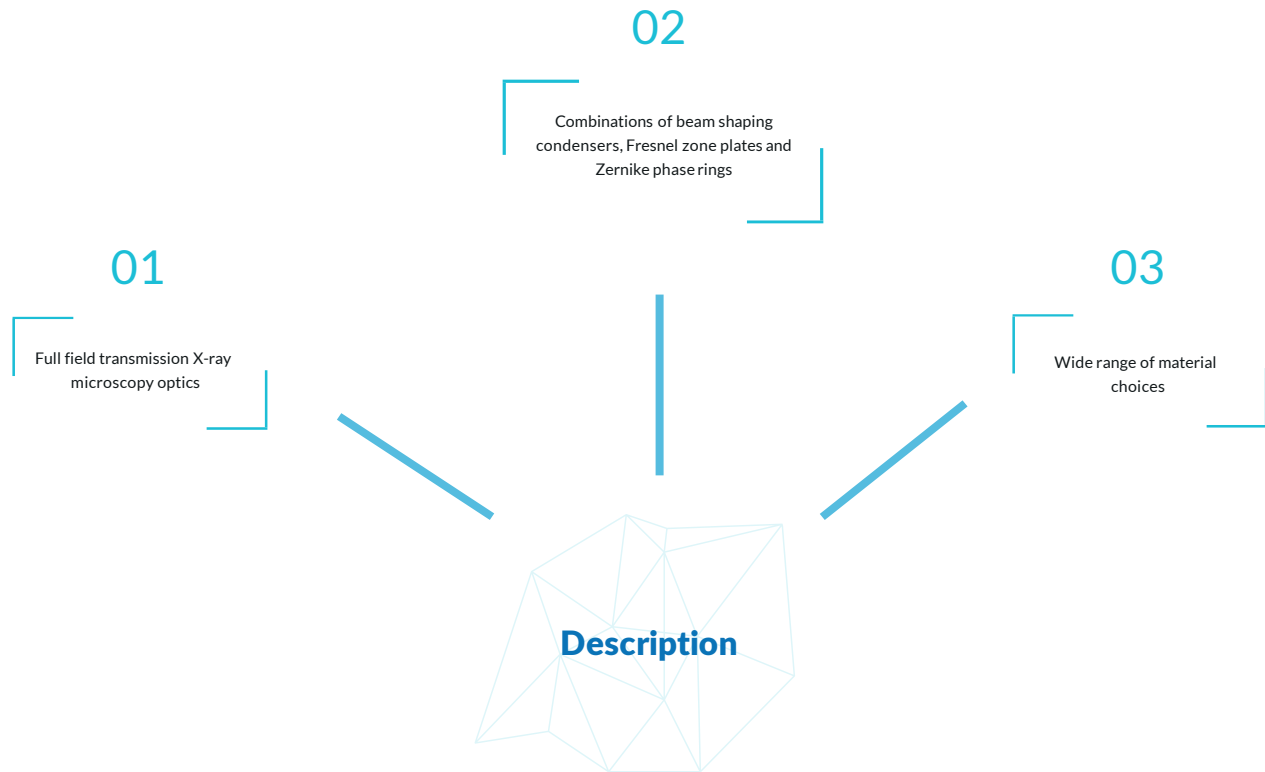
Figure 8.4
Phase corrector plates for Be CRLs



References

1. A. Kubec et al. An achromatic X-ray lens. *Nat. Commun.* 13 (2022), p. 1305
2. F. Seiboth et al. Hard X-ray wavefront correction via refractive phase plates made by additive and subtractive fabrication techniques in *J. Synchrotron Rad.* 27, 1121-1130.

TXM Optical System



References

1. I. Vartiainen et al. Halo suppression in full field X-ray Zernike phase contrast microscopy *Optics Letters* 39 (2014) p. 1601
2. M. Stampanoni et al. Hard X-ray 3D phase-contrast nanoimaging *Physical Review B* 81 (2010) p. 140105
3. I. Vartiainen et al. Artifact characterization and reduction in scanning X-ray Zernike phase contrast microscopy *Optics Express* 23 (2015) p. 13278
4. I. Vartiainen et al. Zernike X-ray Ptychography *Optics Letters* 41 (2016) p. 721
5. M. Storm et al. The Diamond I13 full-field transmission X-ray microscope: a Zernike phase-contrast setup for material sciences *Powder Diffraction* (2020) p. 1

Beamline Supplies

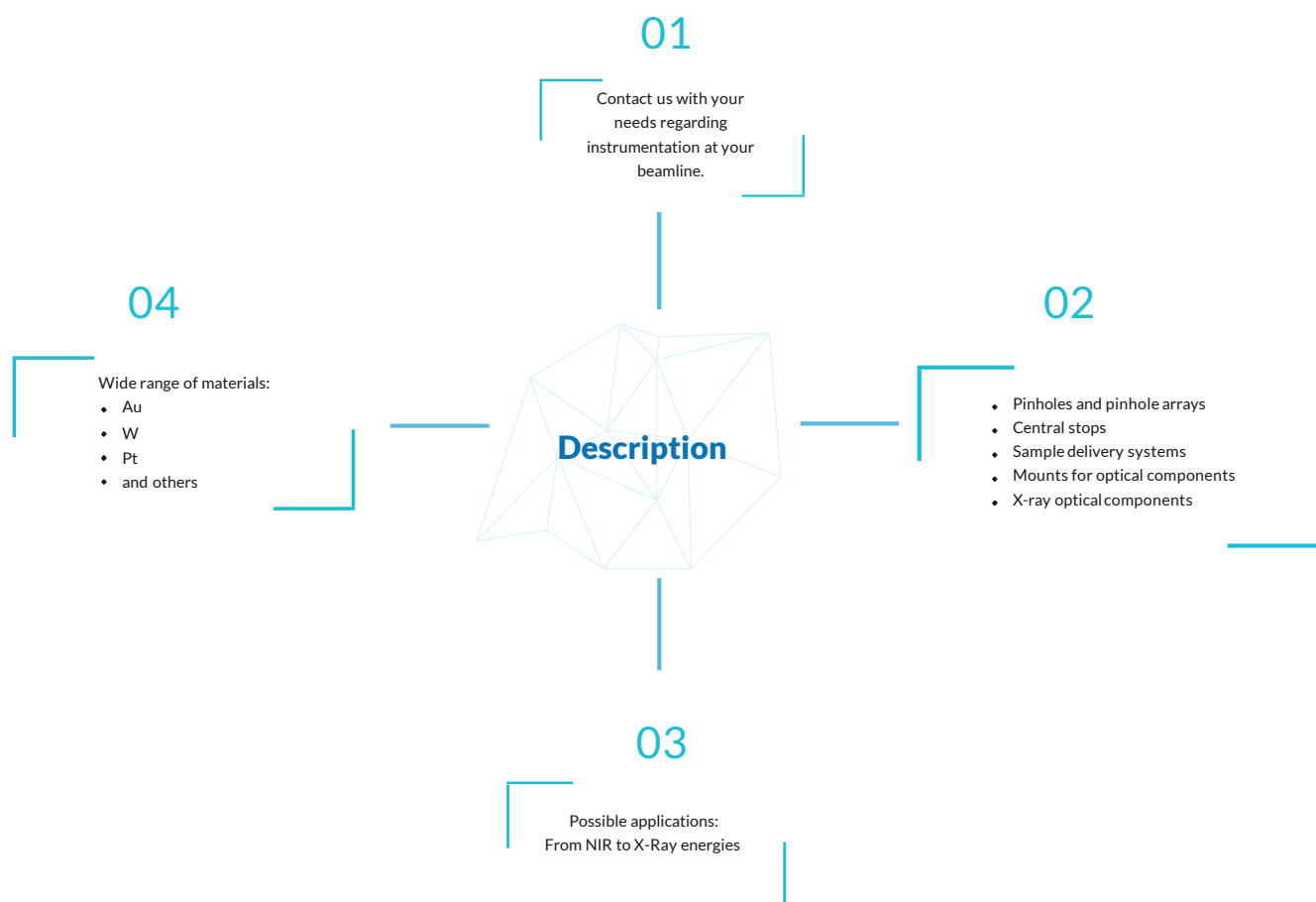


Figure 10.1 Mounted Pinholes

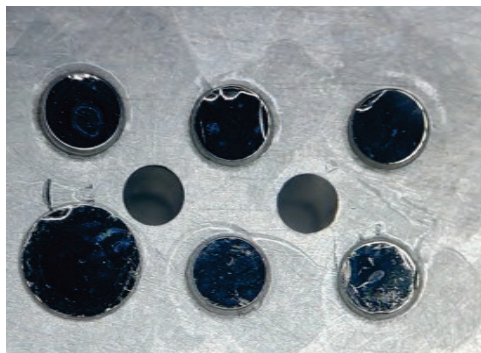
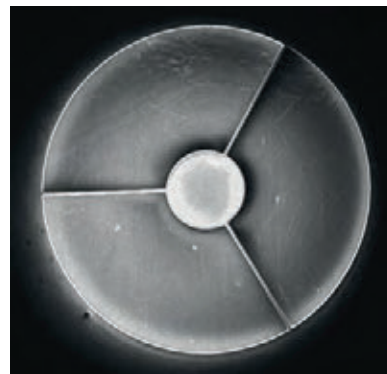


Figure 10.2 Central Stop



Membranes

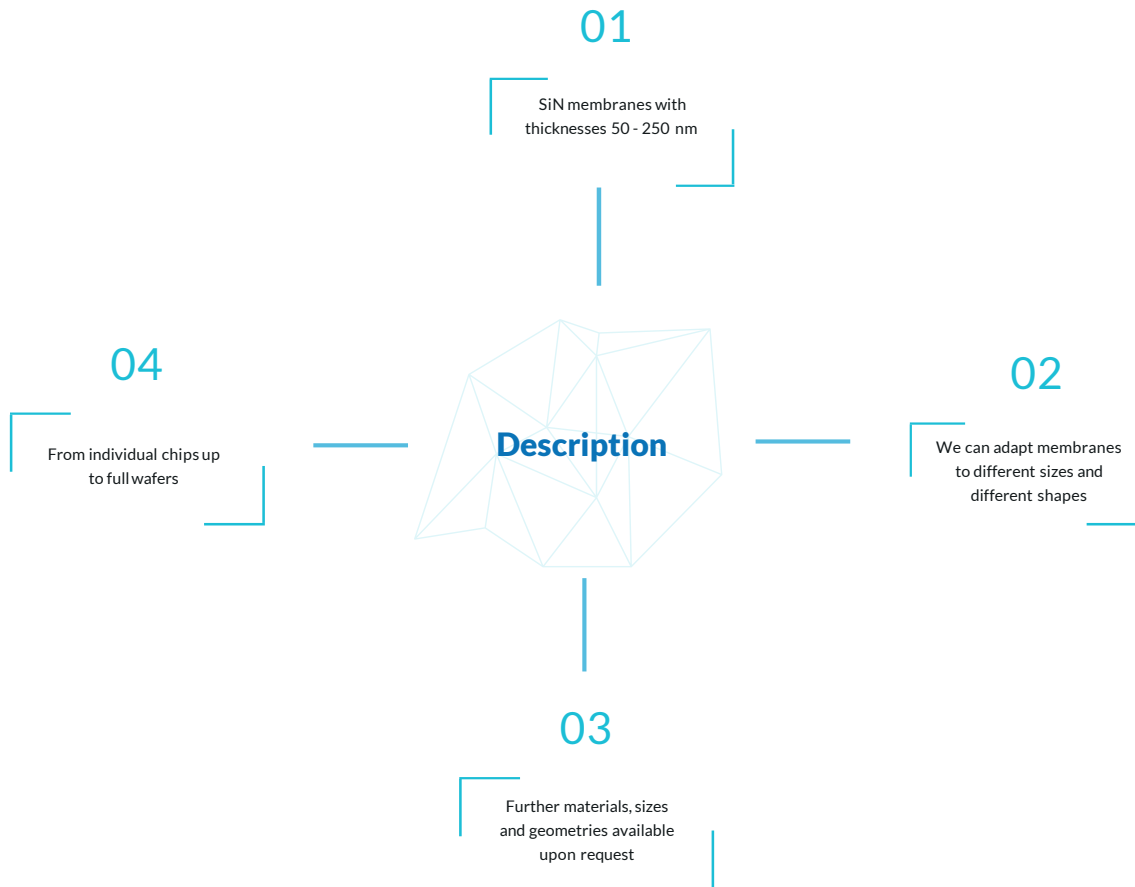


Figure: 11.1
Practical multi-frame arrays that can be cleaved easily into individual membranes

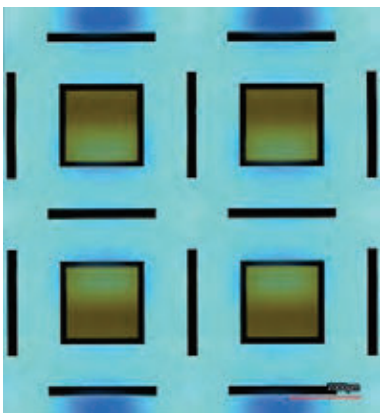
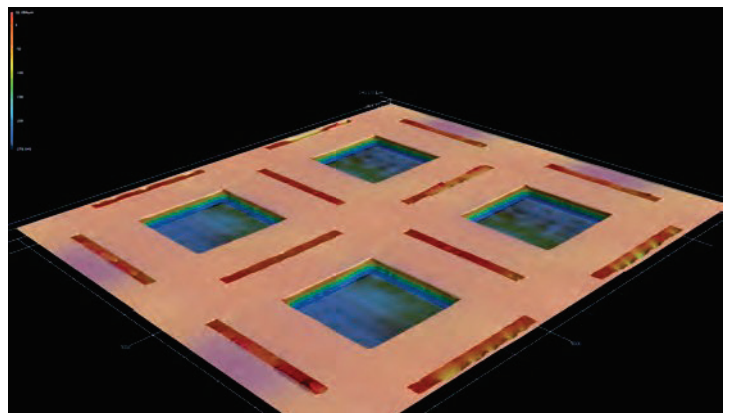


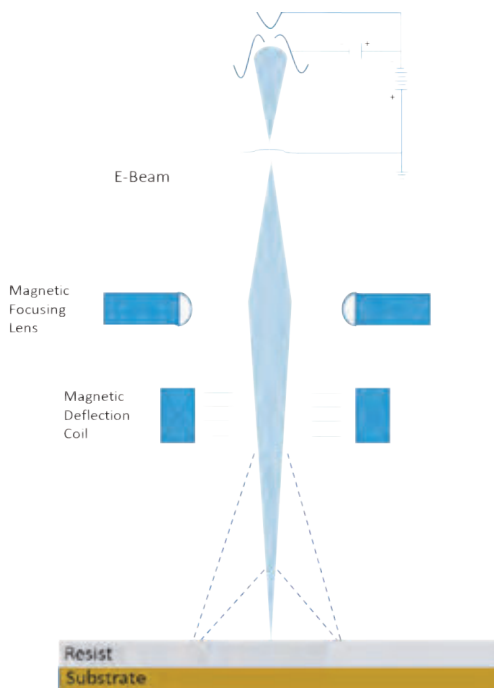
Figure: 11.2
Different roughness classes and various coatings are available



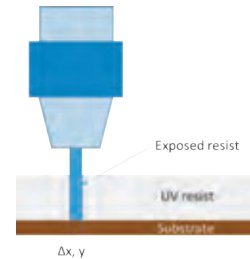
Foundry Service



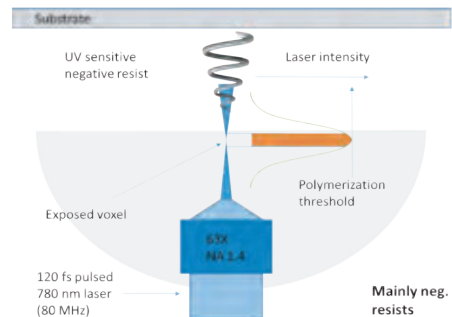
E-Beam lithography



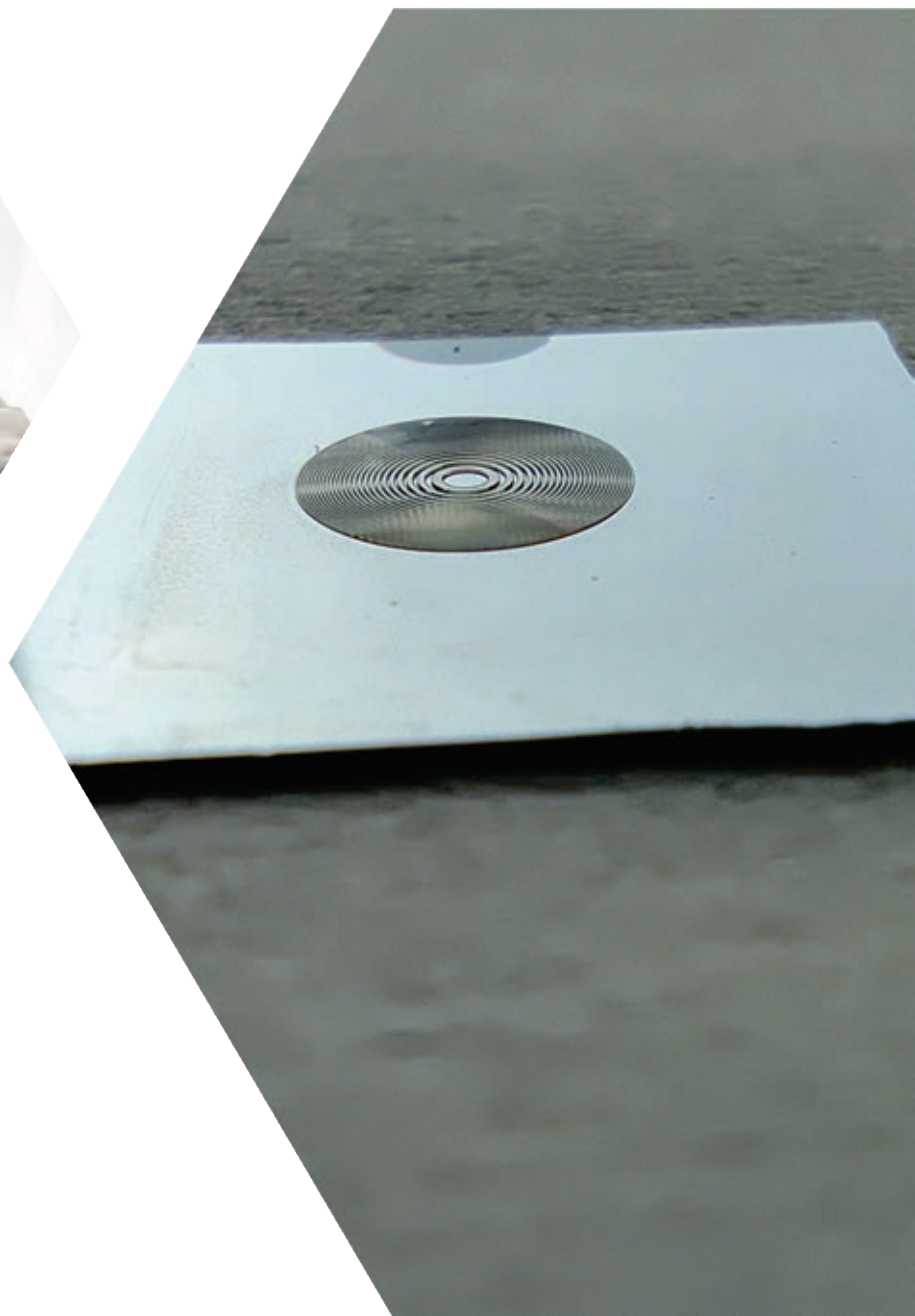
Direct Laser Exposure



2 Photon Polymerization



Contact us now for further information



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